

# Advanced Test Equipment Rentals www.atecorp.com 800-404-ATEC (2832)



# Technical data sheet



# Inductance Analyzers - 3255BL 3255B and 3255BQ

- Frequency ranges from 20 Hz to 1 MHz
- Fast measurement speed up to 20 measurements per second
- 0.1% basic accuracy
- Up to 125 A of DC bias current
- Comprehensive measurement functions
- Straightforward intuitive operation
- Print test results
- GPIB control with LabVIEW<sup>™</sup> driver

# Completely characterize components with comprehensive parametric tests

The 3255B range of inductance analyzers are able to accurately characterise devices in a clear and simple manner. The inductance analyzers are available in three versions 3255BL (200kHz), 3255B (500kHz) and 3255BQ (1 MHz).

At the design stage of component development it is very important to analyse how components performs under different operating conditions. This includes operation over a range of frequencies, AC drive levels or DC bias currents.

The AC drive level can be set between 1 mV and 10 V. DC bias current can be set from 1 mA to 1 A internally (optional). Using the external 3265B range of DC Bias Units bias currents can be set to a maximum of 125 A.

## Specification summary

Measurement functions	Z, Ø, L, C, Rac, Rdc, Q, D, turns ratio
Frequency ranges	20 Hz to 200kHz (3255BL) 20 Hz to 500 kHz (3255B) 20 Hz to 1 MHz (3255BQ)
Basic accuracy	0.1%
Modes	Impedance Multi frequency Bin handler (optional)
DC bias current	1 mA to 1 A - internal (optional)
Interface	GPIB (option)
Measurement speed	Up to 20 measurements/sec

### Printed output of test results

Using the parallel Centronics interface the user can directly print all test results for further analysis and archiving.

In addition, via the optional GPIB interface, the instrument can be controlled from a PC and results can be read back for analysis and storage.

LabVIEW<sup>™</sup> drivers are available on request or can be downloaded from the web site, www.waynekerrtest.com, providing a base from which a user can develop a specific test application.



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## Bin sort

The binning function allows component manufacturers to sort components in up to ten bins. Sorting is carried out either by absolute values or by percentage of values.

# Component tests with up to 125 A DC bias current

The 3255B and 3255BQ enable components to be measured at up to 125 A when optional 3265B DC Bias Units are used. Extended DC bias capability is also available with the 3255BL which uses the 3265B/5A or 3265B/10A to extend the DC bias current available to a maximum of 50A. Up to five of the DC Bias Units can be used in parallel to give a wide range of DC bias currents.

Internal DC bias is available as an option giving DC bias currents from 1 mA to 1 A.

The 3265B has a number of safety and protection features including a safety interlock system to protect users against back EMFs. It is also fully protected against over temperature, excess voltage drop and sense lead failure.



3265B DC Bias Unit can deliver up to 25 A of DC bias current in steps of 0.025 A

## SMD inductor tests up to 50 A

With the addition of the 1009 DC Bias Fixture DC bias currents up to 50 A can be applied to an SMD inductor during component test in order to evaluate the devices thoroughly at operational bias currents. The fixture operates with one or two 3265B/25A Wayne Kerr DC bias units and a 3255B Inductance Analyzer. If two 3265B/25As are used then the optional 5-328-2005 high current lead set will be required.

Four rear panel mounted BNC connectors and two captive high current cables ensure simplicity and ease of use with a 3265B.

Interchangeable component test carriers ensure that the 1009 test fixture may be used with a wide variety of different devices. Blank carriers are available which enable device specific test fixtures to be developed or alternatively a carrier design and manufacturing service is available.

Stable component fixturing ensures high accuracy and repeatable measurements. Enclosed fixtures, with safety interlocks, minimises risk to operators.



1009 DC Bias Fixture enables currents up to 50 A to be applied to an SMD inductor

www.waynekerrtest.com

## sales@waynekerr.info



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# **Technical specifications**

## **Operation modes**

#### Impedance mode

Inductance (L), Impedance (Z), DC Resistance (Rdc) and Capacitance (C). Series or parallel equivalent circuit Loss term: Quality factor (Q), Dissipation factor (D), AC Resistance (Rac) and Phase Angle (Ø) Turns Ratio Percentage difference mode and relative mode on major terms.

#### Multi-frequency mode

Measurement parameters and test conditions set using measurement mode. Up to eight frequencies with absolute or percentage limits on major term with PASS/FAIL indications.

#### **Test conditions**

Low level AC drive

For measurement of L + Q, Ls + Rs, C, Z, Turns Ratio

#### **Frequency ranges**

20 Hz to 200 kHz (3255BL) 20 Hz to 500 kHz (3255B) 20 Hz to 1 MHz (3255BQ)

#### Steps

At least 800 frequency steps are available which may be selected via the keypad or GPIB. Basic accuracy of selected frequency  $\pm 0.01\%$ 

#### **Drive level**

Source impedance 50  $\Omega$  1 mV to 10 V rms into open circuit 50  $\mu A$  to 200 mA rms into short circuit Automatic Level Control (ALC) maintains level applied to Device Under Test (DUT) at ±2%, ±1 mV of set voltage or ±2% ±0.1 mA of set current, reduces to ±4% below 100 Hz.

#### DC bias current (option)

1mA to 1A DC is available from internal, fast settling bias supply over full frequency range. Voltage compliance 14 V minimum DC Accuracy ±2.5 % ±0.25 mA Enabling DC bias inherently reduces measurement accuracy. Safety interlock eliminates operator exposure to high currents.

#### **DC** resistance

Low test level of 100 mV minimises heating of the DUT Short circuit current 10 mA.

#### Bin handler mode (option)

Sort to 1 of 10 bins using absolute or percentage limits. Separate Pass/Fail output. Up to 100 bin limit set-ups stored in non-volatile memory. TTL interface to external bin handler via 25 way D type connector.

#### Option /D1 (non-isolated)

Common 0 V. Bin outputs 0 to 5 V(nominal) with >10 mA current sink capability. **Option /D2 (isolated)** Common 24 V input. Outputs 0 to 24 V with >10 mA current source capability.

#### Measurement speeds

For Impedance, Turns Ratio, DC Resistance 4 speeds selectable for all functions: MAXimum, FAST, MEDium and SLOW

Maximum for remote control. Up to 20 measurements per second for test frequency  $\geq$ 100 Hz. Selecting slower speeds improves accuracy and display resolution.

#### Measurement ranges

 $\begin{array}{l} R \ 0.05 \ m\Omega \ to > 2 \ M\Omega \\ L \ 1 \ nH \ to > 1000 \ H \\ C \ 0.01 \ pF \ to > 250 \ mF \\ Rdc \ 0.5 \ m\Omega \ to \ 50 \ k\Omega \\ Turns \ Ratio \ 100:1 \ to \ 1:100 \end{array}$ 

#### **Accuracy**

 $\begin{array}{l} L/C/Z/Turns \ Ratio \ \pm 0.1\% \\ Q \ \pm 0.1\% \ (Q+1/Q) \\ D \ \pm 0.001 \ (1+D2) \\ Rdc \ \pm 0.5\% \ \pm 1m\Omega \\ Note: \ Ranges \ and \ accuracy \ vary \ with \ measurement \ speed, \ frequency \ and \ options \ chosen \end{array}$ 



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Order code

1J3255BL

1J3255B

1J3255BQ

1J3265B/5A

1J3265B/10A

1J3265B/20A

1J3265B/25A

Order code

5-328-2005

1EVA40100

1EVA40180

1EVA40120 4-324-6009

1EXA20230

1EV1505

1J1009

Order codes and options

3255BL Inductance Analyzer - 200 kHz

3255B Inductance Analyzer - 500 kHz

3255BQ Inductance Analyzer - 1 MHz

/A 1 mA to 1 A internal DC bias

/B GPIB (IEEE-488) interface

5A DC bias unit 3265B/5A

10A DC bias unit 3265B/10A

20A DC bias unit 3265B/20A

(Not compatible with 3255BL)

25A DC bias unit 3265B/25A

(Not compatible with 3255BL)

Supplied with user manual and power cable

Supplied with user manual and power cable

Supplied with user manual and power cable

/D1 Bin handler (cannot be fitted with /D2)

/D2 Bin handler opto-coupled (cannot be fitted with /D1

All auxiliary units are supplied with user manual, power cable,

spare fuses, 4 x BNC to BNC links and daisy chain

Description

Options

link.

Accessories

1009 DC Bias Fixture

Kelvin clips (fine jaws).

Kelvin clips (large jaws)

4-terminal lead set

SMD Tweezers

Bus bars

High current lead set for 1009

Rack mounting kit, 3U x full width

(Unit needs rear support)

Description

**Auxiliary unit** 

### **General data**

#### Input specification

Power supply 230 V AC ±10% or 115 V AC ±10% (selectable) 50 to 400 Hz 150 VA maximum consumption

#### Display

High contrast monochrome LCD  $320 \times 240$  dot with back lighting. Visible area  $115 \times 86$ mm. Viewing angle  $45^{\circ}$ 

#### **Measurement connections**

4 front panel BNC sockets 4-wire (Kelvin) measurements with screen at ground potential Equivalent circuit symbols on screen

#### **Remote control (option)**

Conforms with GPIB IEEE-488.2 and SCPI 1992.0

#### **Printer output**

Centronics/parallel printer port

#### **Environmental conditions**

Temperature range Storage -40 °C to 70 °C Operating 0 °C to 40 °C Full Accuracy 15 °C to 35 °C

Altitude up to 2000m Relative humidity: up to 80% non-condensing Installation category: II (in accordance with IEC664) Pollution degree: 2 (mainly nonconductive) This equipment is intended for indoor use only in non-explosive, non-corrosive atmosphere.

#### Safety

Complies with the requirements of EN61010-1

#### EMC

Complies with EN50081-1, EN50082-1 generic emissions and immunity standards by meeting with the requirements of EN55022, IEC801.2, IEC801.3 and IEC801.4

#### Mechanical (approx. overall)

 Height
 150 mm (6")

 Width
 440 mm ( $17^{3}/_{8}$ ")

 Depth
 520 mm ( $20^{1}/_{2}$ ")

 Weight
 11 kg (24 lb 4 oz)

#### UK

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Wayne Kerr's policy is one of continuous development and consequently the product may vary in detail from the description and specification in this publication.

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